 Searc	ch No	otes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/628,251	DE LEVAL, JEAN
Examiner	Art Unit

John P. Lacyk

3735

	SEARCHED		
Class	Subclass	Date	Examiner
600	29-32,		·
	37		
606	139,141,		
	144-150,		
	222-227		
128	Dig 25	8/31/2006	JPL
Updated	above	12/18/2006	JPL.
		·	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date -	Examiner
	•		
	<u> </u>		
	ce Search Printout	12/19/2006	JPL .

(INCLUDING SEARCH	DATE	EXMR
	DATE	LAIVIR
•		
•		1
<u> </u>		· · · · ·
•		
·		1
•		
•		
•		
,		
•		